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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	784
Number of Logic Elements/Cells	1862
Total RAM Bits	25088
Number of I/O	169
Number of Gates	40000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs40-3pq208i

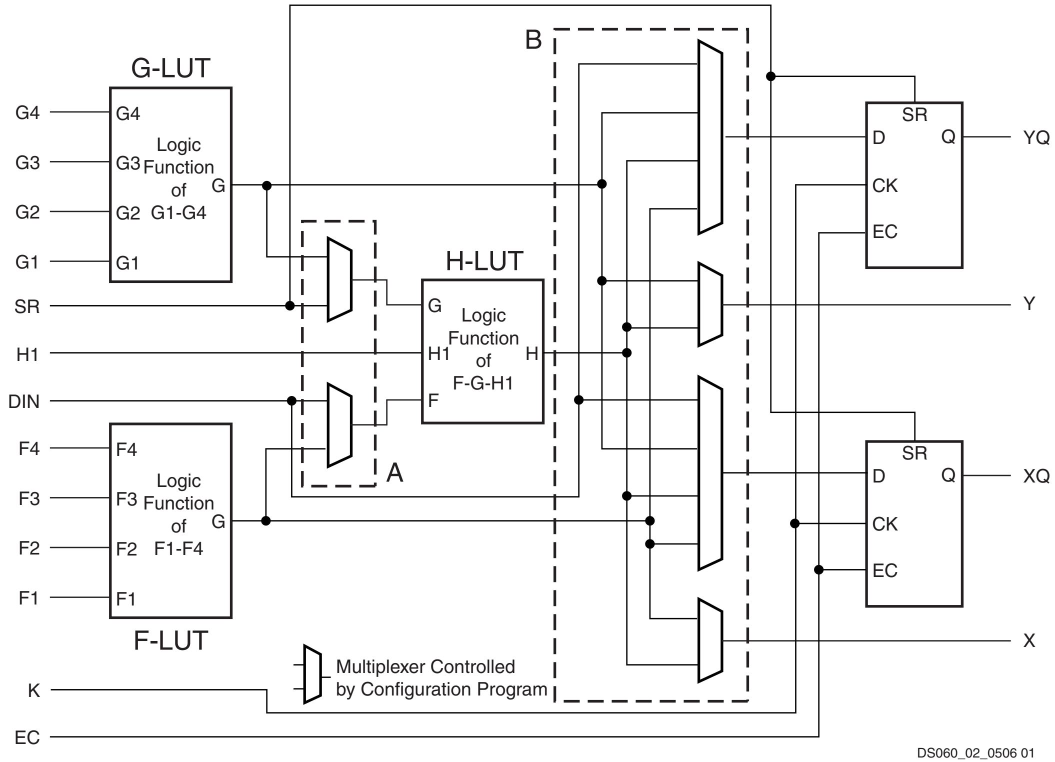


Figure 2: **Spartan/XL Simplified CLB Logic Diagram (some features not shown)**

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

  Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.
- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see Figure 2). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in **Global Signals: GSR and GTS**, page 20.

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in Table 2.

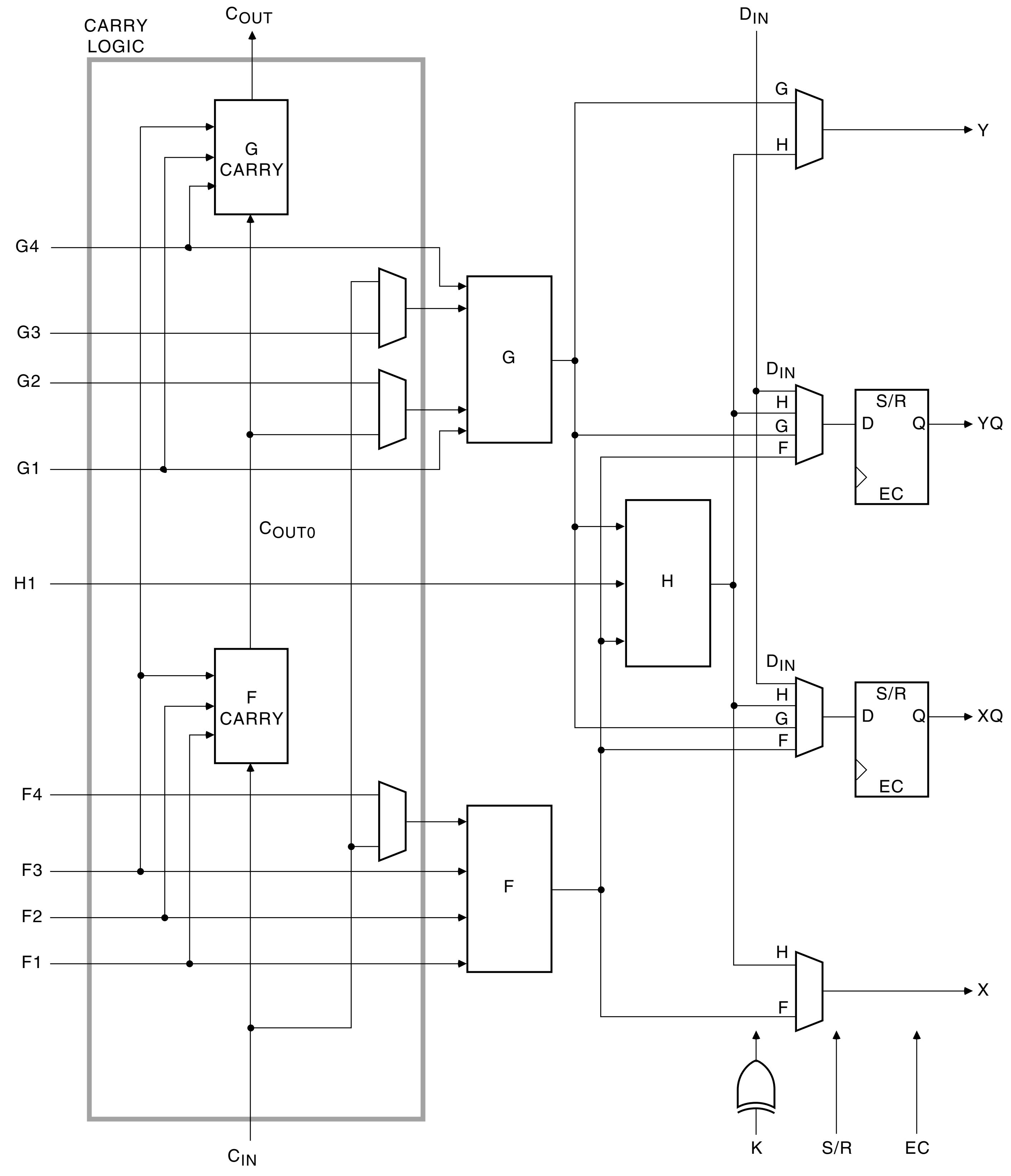


Figure 16: **Fast Carry Logic in Spartan/XL CLB**

On-Chip Oscillator

Spartan/XL devices include an internal oscillator. This oscillator is used to clock the power-on time-out, for configuration memory clearing, and as the source of CCLK in Master configuration mode. The oscillator runs at a nominal 8 MHz frequency that varies with process, V_{CC}, and temperature. The output frequency falls between 4 MHz and 10 MHz.

The oscillator output is optionally available after configuration. Any two of four resynchronized taps of a built-in divider are also available. These taps are at the fourth, ninth, fourteenth and nineteenth bits of the divider. Therefore, if the primary oscillator output is running at the nominal 8 MHz, the user has access to an 8-MHz clock, plus any two of 500 kHz, 16 kHz, 490 Hz and 15 Hz. These frequencies can vary by as much as -50% or +25%.

These signals can be accessed by placing the OSC4 library element in a schematic or in HDL code. The oscillator is automatically disabled after configuration if the OSC4 symbol is not used in the design.

Global Signals: GSR and GTS

Global Set/Reset

A separate Global Set/Reset line, as shown in Figure 3, page 5 for the CLB and Figure 5, page 6 for the IOB, sets or clears each flip-flop during power-up, reconfiguration, or when a dedicated Reset net is driven active. This global net (GSR) does not compete with other routing resources; it uses a dedicated distribution network.

Each flip-flop is configured as either globally set or reset in the same way that the local set/reset (SR) is specified. Therefore, if a flip-flop is set by SR, it is also set by GSR. Similarly, if in reset mode, it is reset by both SR and GSR.

GSR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GSR pin of the STARTUP symbol. (See Figure 19.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the GSR signal. Alternatively, GSR can be driven from any internal node.

Global 3-State

A separate Global 3-state line (GTS) as shown in Figure 6, page 7 forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. GTS does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. This is similar to what is shown in Figure 19 for GSR except the IBUF would be connected to GTS. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-state signal. Alternatively, GTS can be driven from any internal node.

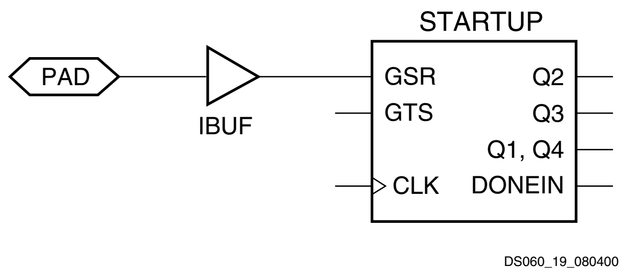


Figure 19: **Symbols for Global Set/Reset**

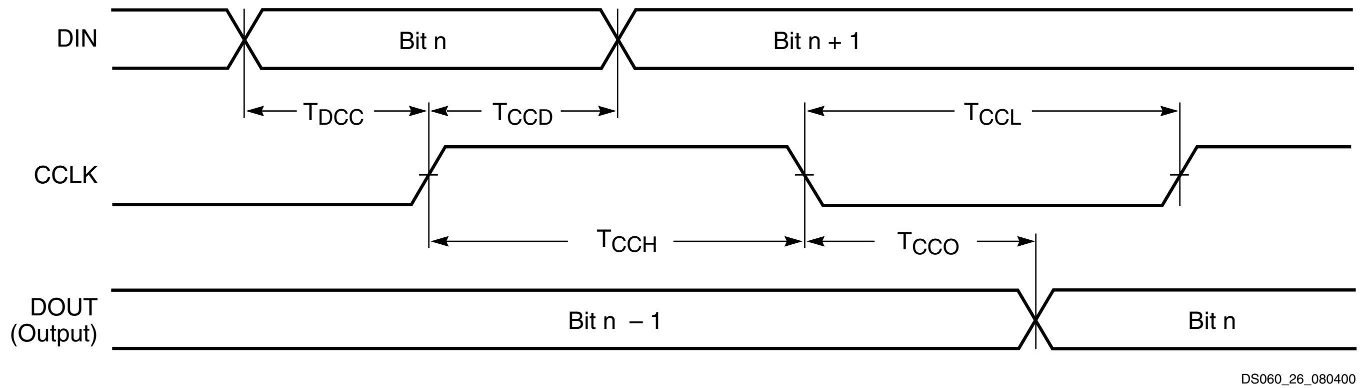
Boundary Scan

The "bed of nails" has been the traditional method of testing electronic assemblies. This approach has become less appropriate, due to closer pin spacing and more sophisticated assembly methods like surface-mount technology and multi-layer boards. The IEEE Boundary Scan Standard 1149.1 was developed to facilitate board-level testing of electronic assemblies. Design and test engineers can embed a standard test logic structure in their device to achieve high fault coverage for I/O and internal logic. This structure is easily implemented with a four-pin interface on any boundary scan compatible device. IEEE 1149.1-compatible devices may be serial daisy-chained together, connected in parallel, or a combination of the two.

The Spartan and Spartan-XL families implement IEEE 1149.1-compatible BYPASS, PRELOAD/SAMPLE and EXTEST boundary scan instructions. When the boundary scan configuration option is selected, three normal user I/O pins become dedicated inputs for these functions. Another user output pin becomes the dedicated boundary scan output. The details of how to enable this circuitry are covered later in this section.

By exercising these input signals, the user can serially load commands and data into these devices to control the driving of their outputs and to examine their inputs. This method is an improvement over bed-of-nails testing. It avoids the need to over-drive device outputs, and it reduces the user interface to four pins. An optional fifth pin, a reset for the control logic, is described in the standard but is not implemented in the Spartan/XL devices.

The dedicated on-chip logic implementing the IEEE 1149.1 functions includes a 16-state machine, an instruction register and a number of data registers. The functional details can be found in the IEEE 1149.1 specification and are also discussed in the Xilinx application note: "*Boundary Scan in FPGA Devices*."



Symbol		Description	Min	Max	Units
T_{DCC}	CCLK	DIN setup	20	-	ns
T_{CCD}		DIN hold	0	-	ns
T_{CCO}		DIN to DOUT	-	30	ns
T_{CCH}		High time	40	-	ns
T_{CCL}		Low time	40	-	ns
F_{CC}		Frequency	-	12.5	MHz

Notes:
1. Configuration must be delayed until the $\overline{\text{INIT}}$ pins of all daisy-chained FPGAs are High.

Figure 26: **Slave Serial Mode Programming Switching Characteristics**

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

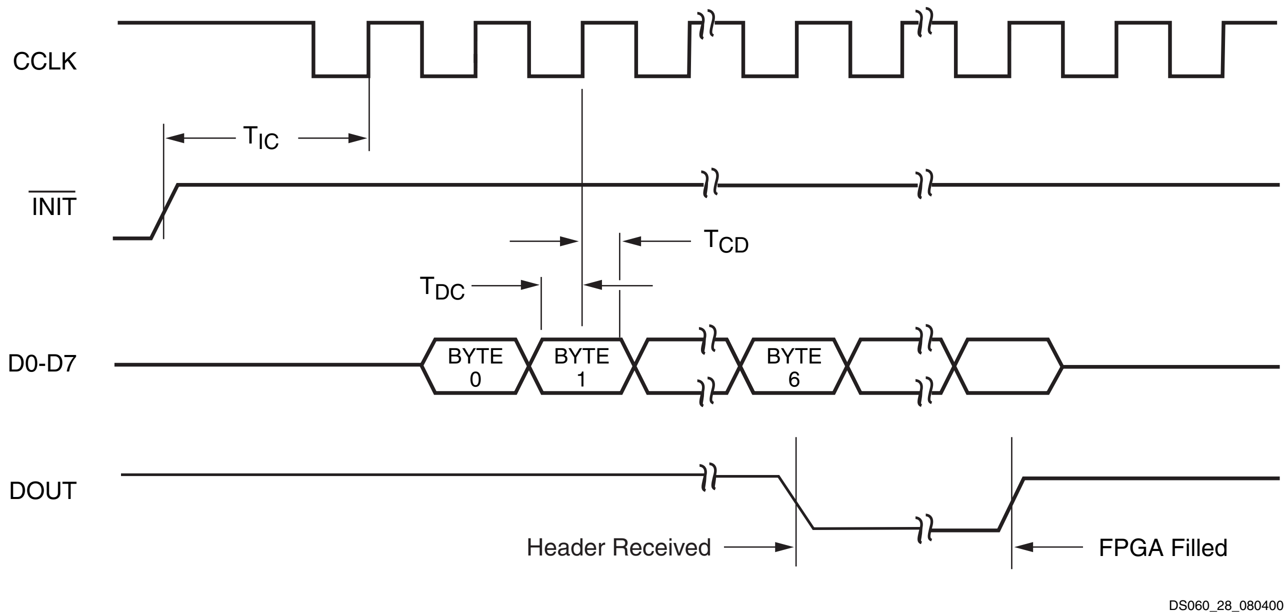
The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized



Symbol		Description	Min	Max	Units
T_{IC}	CCLK	$\overline{\text{INIT}}$ (High) setup time	5	-	µs
T_{DC}		D0-D7 setup time	20	-	ns
T_{CD}		D0-D7 hold time	0	-	ns
T_{CCH}		CCLK High time	45	-	ns
T_{CCL}		CCLK Low time	45	-	ns
F_{CC}		CCLK Frequency	-	10	MHz

Notes:
1. If not driven by the preceding DOUT, CS1 *must* remain High until the device is fully configured.

Figure 28: **Express Mode Programming Switching Characteristics**

Setting CCLK Frequency

In Master mode, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for Spartan/XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for Spartan/XL devices. The frequency is changed to fast by an option when running the bitstream generation software.

Data Stream Format

The data stream ("bitstream") format is identical for both serial configuration modes, but different for the Spartan-XL family Express mode. In Express mode, the device becomes active when DONE goes High, therefore no length count is required. Additionally, CRC error checking is not supported in Express mode. The data stream format is shown in Table 16. Bit-serial data is read from left to right. Express mode data is shown with D0 at the left and D7 at the right.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones (or 24 fill bits, in Spartan-XL family Express mode). This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 17). Each frame begins with a start field and ends with an error check. In serial modes, a postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All start-up bytes are "don't cares".

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0](1)
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b(2)
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes(3)	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

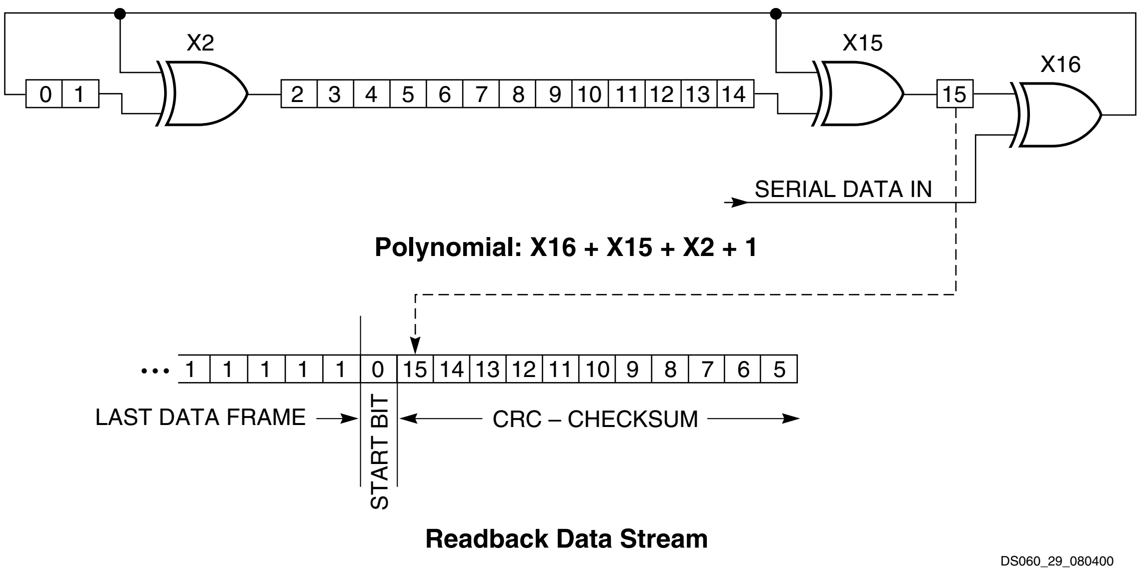


Figure 29: **Circuit for Generating CRC-16**

Configuration Sequence

There are four major steps in the Spartan/XL FPGA power-up configuration sequence.

- Configuration Memory Clear
- Initialization
- Configuration
- Start-up

The full process is illustrated in Figure 30.

Configuration Memory Clear

When power is first applied or is reapplied to an FPGA, an internal circuit forces initialization of the configuration logic. When V_{CC} reaches an operational level, and the circuit passes the write and read test of a sample pair of configuration bits, a time delay is started. This time delay is nominally 16 ms. The delay is four times as long when in Master Serial Mode to allow ample time for all slaves to reach a stable V_{CC}. When all $\overline{\text{INIT}}$ pins are tied together, as recommended, the longest delay takes precedence. Therefore, devices with different time delays can easily be mixed and matched in a daisy chain.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the $\overline{\text{PROGRAM}}$ pin Low. During this time delay, or as long as the $\overline{\text{PROGRAM}}$ input is asserted, the configuration logic is held in a Configuration Memory Clear state. The configuration-memory frames are consecutively initialized, using the internal oscillator.

At the end of each complete pass through the frame addressing, the power-on time-out delay circuitry and the level of the $\overline{\text{PROGRAM}}$ pin are tested. If neither is asserted, the logic initiates one additional clearing of the configuration frames and then tests the $\overline{\text{INIT}}$ input.

Initialization

During initialization and configuration, user pins HDC, $\overline{\text{LDC}}$, $\overline{\text{INIT}}$ and DONE provide status outputs for the system interface. The outputs $\overline{\text{LDC}}$, $\overline{\text{INIT}}$ and DONE are held Low and HDC is held High starting at the initial application of power.

The open drain $\overline{\text{INIT}}$ pin is released after the final initialization pass through the frame addresses. There is a deliberate delay before a Master-mode device recognizes an inactive $\overline{\text{INIT}}$. Two internal clocks after the $\overline{\text{INIT}}$ pin is recognized as High, the device samples the MODE pin to determine the configuration mode. The appropriate interface lines become active and the configuration preamble and data can be loaded.

Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs and IOBs, as well as the content of function generators used as RAMs.

Although readback can be performed while the device is operating, for best results and to freeze a known capture state, it is recommended that the clock inputs be stopped until readback is complete.

Readback of Spartan-XL family Express mode bitstreams results in data that does not resemble the original bitstream, because the bitstream format differs from other modes.

Spartan/XL FPGA Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, instantiate the READBACK library symbol and attach the appropriate pad symbols, as shown in Figure 32.

After Readback has been initiated by a Low-to-High transition on RDBK.TRIG, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low) of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.

Readback Options

Readback options are: Readback Capture, Readback Abort, and Clock Select. They are set with the bitstream generation software.

Readback Capture

When the Readback Capture option is selected, the data stream includes sampled values of CLB and IOB signals. The rising edge of RDBK.TRIG latches the inverted values of the four CLB outputs, the IOB output flip-flops and the input signals I1 and I2. Note that while the bits describing configuration (interconnect, function generators, and RAM content) are *not* inverted, the CLB and IOB output signals *are* inverted. RDBK.TRIG is located in the lower-left corner of the device.

When the Readback Capture option is not selected, the values of the capture bits reflect the configuration data originally written to those memory locations. If the RAM capability of the CLBs is used, RAM data are available in Readback, since they directly overwrite the F and G function-table configuration of the CLB.

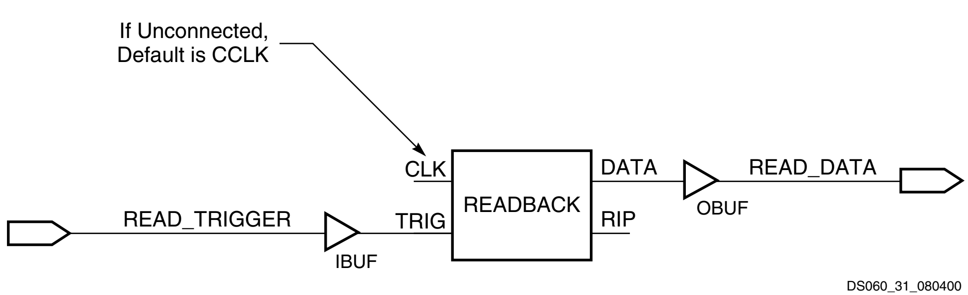


Figure 32: **Readback Example**

Spartan Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan Family Absolute Maximum Ratings(1)

Symbol	Description		Value	Units
V_{CC}	Supply voltage relative to GND		–0.5 to +7.0	V
V_{IN}	Input voltage relative to GND(2,3)		–0.5 to V_{CC} +0.5	V
V_{TS}	Voltage applied to 3-state output(2,3)		–0.5 to V_{CC} +0.5	V
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature	Plastic packages	+125	°C

Notes:
1. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
2. Maximum DC overshoot (above V_{CC}) or undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
3. Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to –2.0V or overshoot to +7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
4. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CC}	Supply voltage relative to GND, T_J = 0°C to +85°C	Commercial	4.75	5.25	V
	Supply voltage relative to GND, T_J = –40°C to +100°C(1)	Industrial	4.5	5.5	V
V_{IH}	High-level input voltage(2)	TTL inputs	2.0	V_{CC}	V
		CMOS inputs	70%	100%	V_{CC}
V_{IL}	Low-level input voltage(2)	TTL inputs	0	0.8	V
		CMOS inputs	0	20%	V_{CC}
T_{IN}	Input signal transition time		-	250	ns

Notes:
1. At junction temperatures above those listed as Recommended Operating Conditions, all delay parameters increase by 0.35% per °C.
2. Input and output measurement thresholds are: 1.5V for TTL and 2.5V for CMOS.

Spartan Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Max	Units
V_{OH}	High-level output voltage @ I_{OH} = –4.0 mA, V_{CC} min	TTL outputs	2.4	-	V
	High-level output voltage @ I_{OH} = –1.0 mA, V_{CC} min	CMOS outputs	V_{CC} – 0.5	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min(1)	TTL outputs	-	0.4	V
		CMOS outputs	-	0.4	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		3.0	-	V
I_{CCO}	Quiescent FPGA supply current(2)	Commercial	-	3.0	mA
		Industrial	-	6.0	mA
I_L	Input or output leakage current		–10	+10	μA
C_{IN}	Input capacitance (sample tested)		-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 5V (sample tested)		0.02	-	mA

Notes:
1. With 50% of the outputs simultaneously sinking 12 mA, up to a maximum of 64 pins.
2. With no output current loads, no active input pull-up resistors, all package pins at V_{CC} or GND, and the FPGA configured with a Tie option.

Spartan Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
T_{PG}	From pad through Primary buffer, to any clock K	XCS05	2.0	4.0	ns
		XCS10	2.4	4.3	ns
		XCS20	2.8	5.4	ns
		XCS30	3.2	5.8	ns
		XCS40	3.5	6.4	ns
T_{SG}	From pad through Secondary buffer, to any clock K	XCS05	2.5	4.4	ns
		XCS10	2.9	4.7	ns
		XCS20	3.3	5.8	ns
		XCS30	3.6	6.2	ns
		XCS40	3.9	6.7	ns

Spartan Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-4		-3		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	3.0	-	4.0	-	ns
T_{CL}	Clock Low time	3.0	-	4.0	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.2	-	1.6	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	2.0	-	2.7	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.7	-	2.2	ns
CLB Fast Carry Logic						
T_{OPCY}	Operand inputs (F1, F2, G1, G4) to C_{OUT}	-	1.7	-	2.1	ns
T_{ASCY}	Add/Subtract input (F3) to C_{OUT}	-	2.8	-	3.7	ns
T_{INCY}	Initialization inputs (F1, F3) to C_{OUT}	-	1.2	-	1.4	ns
T_{SUM}	C_{IN} through function generators to X/Y outputs	-	2.0	-	2.6	ns
T_{BYP}	C_{IN} to C_{OUT}, bypass function generators	-	0.5	-	0.6	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop outputs Q	-	2.1	-	2.8	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	1.8	-	2.4	-	ns
T_{IHCK}	F/G inputs via H	2.9	-	3.9	-	ns
T_{HH1CK}	C inputs via H1 through H	2.3	-	3.3	-	ns
T_{DICK}	C inputs via DIN	1.3	-	2.0	-	ns
T_{ECCK}	C inputs via EC	2.0	-	2.6	-	ns
T_{RCK}	C inputs via S/R, going Low (inactive)	2.5	-	4.0	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	3.0	-	4.0	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	3.0	-	4.0	ns
Global Set/Reset						
T_{MRW}	Minimum GSR pulse width	11.5	-	13.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 50 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	166	-	125	MHz

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Single Port RAM	Size(1)	Speed Grade -4 Min	-4 Max	-3 Min	-3 Max	Units
Write Operation							
T_{WCS}	Address write cycle time (clock K period)	16x2	8.0	-	11.6	-	ns
T_{WCTS}		32x1	8.0	-	11.6	-	ns
T_{WPS}	Clock K pulse width (active edge)	16x2	4.0	-	5.8	-	ns
T_{WPTS}		32x1	4.0	-	5.8	-	ns
T_{ASS}	Address setup time before clock K	16x2	1.5	-	2.0	-	ns
T_{ASTS}		32x1	1.5	-	2.0	-	ns
T_{AHS}	Address hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{AHTS}		32x1	0.0	-	0.0	-	ns
T_{DSS}	DIN setup time before clock K	16x2	1.5	-	2.7	-	ns
T_{DSTS}		32x1	1.5	-	1.7	-	ns
T_{DHS}	DIN hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{DHTS}		32x1	0.0	-	0.0	-	ns
T_{WSS}	WE setup time before clock K	16x2	1.5	-	1.6	-	ns
T_{WSTS}		32x1	1.5	-	1.6	-	ns
T_{WHS}	WE hold time after clock K	16x2	0.0	-	0.0	-	ns
T_{WHTS}		32x1	0.0	-	0.0	-	ns
T_{WOS}	Data valid after clock K	16x2	-	6.5	-	7.9	ns
T_{WOTS}		32x1	-	7.0	-	9.3	ns
Read Operation							
T_{RC}	Address read cycle time	16x2	2.6	-	2.6	-	ns
T_{RCT}		32x1	3.8	-	3.8	-	ns
T_{ILO}	Data valid after address change (no Write Enable)	16x2	-	1.2	-	1.6	ns
T_{IHO}		32x1	-	2.0	-	2.7	ns
T_{ICK}	Address setup time before clock K	16x2	1.8	-	2.4	-	ns
T_{IHCK}		32x1	2.9	-	3.9	-	ns

Notes:
1. Timing for 16 x 1 RAM option is identical to 16 x 2 RAM timing.

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (continued)

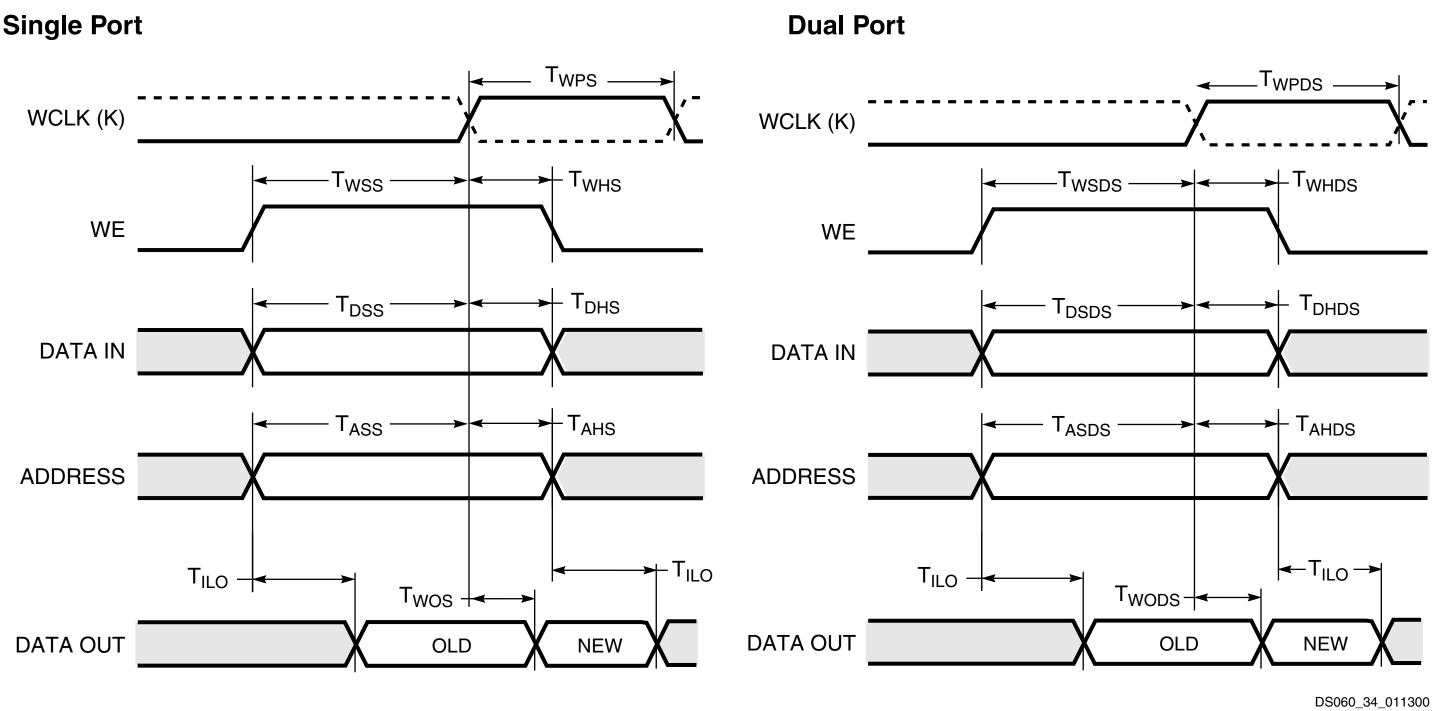
All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and are expressed in nanoseconds unless otherwise noted.

Dual-Port RAM Synchronous (Edge-Triggered) Write Operation Characteristics

Symbol	Dual Port RAM	Size(1)	-4		-3		Units
			Min	Max	Min	Max	
Write Operation							
T_{WCDS}	Address write cycle time (clock K period)	16x1	8.0	-	11.6	-	ns
T_{WPDS}	Clock K pulse width (active edge)	16x1	4.0	-	5.8	-	ns
T_{ASDS}	Address setup time before clock K	16x1	1.5	-	2.1	-	ns
T_{AHDS}	Address hold time after clock K	16x1	0	-	0	-	ns
T_{DSDS}	DIN setup time before clock K	16x1	1.5	-	1.6	-	ns
T_{DHDS}	DIN hold time after clock K	16x1	0	-	0	-	ns
T_{WSDS}	WE setup time before clock K	16x1	1.5	-	1.6	-	ns
T_{WHDS}	WE hold time after clock K	16x1	0	-	0	-	ns
T_{WODS}	Data valid after clock K	16x1	-	6.5	-	7.0	ns

Notes:
1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan Family CLB RAM Synchronous (Edge-Triggered) Write Timing



Spartan Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report.

Spartan Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade -4 Max	Speed Grade -3 Max	Units
Global Primary Clock to TTL Output using OFF					
T_{ICKOF}	Fast	XCS05	5.3	8.7	ns
		XCS10	5.7	9.1	ns
		XCS20	6.1	9.3	ns
		XCS30	6.5	9.4	ns
		XCS40	6.8	10.2	ns
T_{ICKO}	Slew-rate limited	XCS05	9.0	11.5	ns
		XCS10	9.4	12.0	ns
		XCS20	9.8	12.2	ns
		XCS30	10.2	12.8	ns
		XCS40	10.5	12.8	ns
Global Secondary Clock to TTL Output using OFF					
T_{ICKSOF}	Fast	XCS05	5.8	9.2	ns
		XCS10	6.2	9.6	ns
		XCS20	6.6	9.8	ns
		XCS30	7.0	9.9	ns
		XCS40	7.3	10.7	ns
T_{ICKSO}	Slew-rate limited	XCS05	9.5	12.0	ns
		XCS10	9.9	12.5	ns
		XCS20	10.3	12.7	ns
		XCS30	10.7	13.2	ns
		XCS40	11.0	14.3	ns
Delay Adder for CMOS Outputs Option					
T_{CMOSOF}	Fast	All devices	0.8	1.0	ns
T_{CMOSO}	Slew-rate limited	All devices	1.5	2.0	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column,and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load. For different loads, see Figure 34.
3. OFF = Output Flip-Flop

Spartan Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -4 Min	Speed Grade -4 Max	Speed Grade -3 Min	Speed Grade -3 Max	Units
Setup Times - TTL Inputs[1]							
T_{ECIK}	Clock Enable (EC) to Clock (IK), no delay	All devices	1.6	-	2.1	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.5	-	2.0	-	ns
Hold Times							
T_{IKEC}	Clock Enable (EC) to Clock (IK), no delay	All devices	0.0	-	0.9	-	ns
	All Other Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays - TTL Inputs[1]							
T_{PID}	Pad to I1, I2	All devices	-	1.5	-	2.0	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.8	-	3.6	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	2.7	-	2.8	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	3.2	-	3.9	ns
Delay Adder for Input with Delay Option							
T_{Delay}	$T_{ECIKD} = T_{ECIK} + T_{Delay}$	XCS05	3.6	-	4.0	-	ns
	$T_{PICKD} = T_{PICK} + T_{Delay}$	XCS10	3.7	-	4.1	-	ns
	$T_{PDLI} = T_{PLI} + T_{Delay}$	XCS20	3.8	-	4.2	-	ns
		XCS30	4.5	-	5.0	-	ns
		XCS40	5.5	-	5.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5	-	13.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05	-	9.0	-	11.3	ns
		XCS10	-	9.5	-	11.9	ns
		XCS20	-	10.0	-	12.5	ns
		XCS30	-	10.5	-	13.1	ns
		XCS40	-	11.0	-	13.8	ns

Notes:
1. Delay adder for CMOS Inputs option: for -3 speed grade, add 0.4 ns; for -4 speed grade, add 0.2 ns.
2. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
3. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade				Units
			-4		-3		
			Min	Max	Min	Max	
Clocks							
T_{CH}	Clock High	All devices	3.0	-	4.0	-	ns
T_{CL}	Clock Low	All devices	3.0	-	4.0	-	ns
Propagation Delays - TTL Outputs(1,2)							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.3	-	4.5	ns
T_{OKPOS}	Clock (OK to Pad, slew-rate limited	All devices	-	6.9	-	7.0	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	3.6	-	4.8	ns
T_{OPS}	Output (O) to Pad, slew-rate limited	All devices	-	7.2	-	7.3	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	3.0	-	3.8	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	6.0	-	7.3	ns
T_{TSONS}	3-state to Pad active and valid, slew-rate limited	All devices	-	9.6	-	9.8	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	2.5	-	3.8	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	2.0	-	2.7	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.0	-	0.5	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	11.5		13.5		ns
T_{RPO}	Delay from GSR input to any Pad	XCS05	-	12.0	-	15.0	ns
		XCS10	-	12.5	-	15.7	ns
		XCS20	-	13.0	-	16.2	ns
		XCS30	-	13.5	-	16.9	ns
		XCS40	-	14.0	-	17.5	ns

Notes:

1. Delay adder for CMOS Outputs option (with fast slew rate option): for -3 speed grade, add 1.0 ns; for -4 speed grade, add 0.8 ns.
2. Delay adder for CMOS Outputs option (with slow slew rate option): for -3 speed grade, add 2.0 ns; for -4 speed grade, add 1.5 ns.
3. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
4. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade -5 Min	-5 Max	-4 Min	-4 Max	Units
Setup Times							
T_{ECIK}	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T_{POCK}	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Times							
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays							
T_{PID}	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Adder for Input with Full Delay Option							
T_{Delay}	$T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05XL	4.0	-	4.7	-	ns
		XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

Notes:
1. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

Spartan-XL Family IOB Output Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values are expressed in nanoseconds unless otherwise noted.

Symbol	Description	Device	Speed Grade -5 Min	-5 Max	-4 Min	-4 Max	Units
Propagation Delays							
T_{OKPOF}	Clock (OK) to Pad, fast	All devices	-	3.2	-	3.7	ns
T_{OPF}	Output (O) to Pad, fast	All devices	-	2.5	-	2.9	ns
T_{TSHZ}	3-state to Pad High-Z (slew-rate independent)	All devices	-	2.8	-	3.3	ns
T_{TSONF}	3-state to Pad active and valid, fast	All devices	-	2.6	-	3.0	ns
T_{OFPF}	Output (O) to Pad via Output MUX, fast	All devices	-	3.7	-	4.4	ns
T_{OKFPF}	Select (OK) to Pad via Output MUX, fast	All devices	-	3.3	-	3.9	ns
T_{SLOW}	For Output SLOW option add	All devices	-	1.5	-	1.7	ns
Setup and Hold Times							
T_{OOK}	Output (O) to clock (OK) setup time	All devices	0.5	-	0.5	-	ns
T_{OKO}	Output (O) to clock (OK) hold time	All devices	0.0	-	0.0	-	ns
T_{ECOK}	Clock Enable (EC) to clock (OK) setup time	All devices	0.0	-	0.0	-	ns
T_{OKEC}	Clock Enable (EC) to clock (OK) hold time	All devices	0.1	-	0.2	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RPO}	Delay from GSR input to any Pad	XCS05XL	-	11.9	-	14.0	ns
		XCS10XL	-	12.4	-	14.5	ns
		XCS20XL	-	12.9	-	15.0	ns
		XCS30XL	-	13.9	-	16.0	ns
		XCS40XL	-	14.9	-	17.0	ns

Notes:

1. Output timing is measured at ~50% V_{CC} threshold, with 50 pF external capacitive loads including test fixture. Slew-rate limited output rise/fall times are approximately two times longer than fast output rise/fall times.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
VCC	P33	P25	N1	P37	-
Not Connect-ed(1) PWRDWN(2)	P34	P26	N2	P38	174 (1)
I/O, PGCK2(1) GCK3(2)	P35	P27	M3	P39	175(3)
I/O (HDC)	P36	P28	N3	P40	178 (3)
I/O	-	-	K4	P41	181 (3)
I/O	-	-	L4	P42	184 (3)
I/O	-	P29	M4	P43	187 (3)
I/O (LDC)	P37	P30	N4	P44	190 (3)
GND	-	-	K5	P45	-
I/O	-	-	L5	P46	193 (3)
I/O	-	-	M5	P47	196 (3)
I/O	P38	P31	N5	P48	199 (3)
I/O	P39	P32	K6	P49	202 (3)
I/O	-	P33	L6	P50	205 (3)
I/O	-	P34	M6	P51	208 (3)
I/O	P40	P35	N6	P52	211 (3)
I/O (INIT)	P41	P36	M7	P53	214 (3)
VCC	P42	P37	N7	P54	-
GND	P43	P38	L7	P55	-
I/O	P44	P39	K7	P56	217 (3)
I/O	P45	P40	N8	P57	220 (3)
I/O	-	P41	M8	P58	223 (3)
I/O	-	P42	L8	P59	226 (3)
I/O	P46	P43	K8	P60	229 (3)
I/O	P47	P44	N9	P61	232 (3)
I/O	-	-	M9	P62	235 (3)
I/O	-	-	L9	P63	238 (3)
GND	-	-	K9	P64	-
I/O	P48	P45	N10	P65	241 (3)
I/O	P49	P46	M10	P66	244 (3)
I/O	-	-	L10	P67	247 (3)
I/O	-	-	N11	P68	250 (3)
I/O	P50	P47	M11	P69	253 (3)
I/O, SGCK3(1) GCK4(2)	P51	P48	L11	P70	256 (3)
GND	P52	P49	N12	P71	-
DONE	P53	P50	M12	P72	-
VCC	P54	P51	N13	P73	-
PROGRAM	P55	P52	M13	P74	-
I/O (D7(2))	P56	P53	L12	P75	259 (3)

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84(4)	VQ100	CS144(2,4)	TQ144	Bndry Scan
I/O, PGCK3(1) GCK5(2)	P57	P54	L13	P76	262 (3)
I/O	-	-	K10	P77	265 (3)
I/O	-	-	K11	P78	268 (3)
I/O (D6(2))	P58	P55	K12	P79	271 (3)
I/O	-	P56	K13	P80	274 (3)
GND	-	-	J10	P81	-
I/O	-	-	J11	P82	277 (3)
I/O	-	-	J12	P83	280 (3)
I/O (D5(2))	P59	P57	J13	P84	283 (3)
I/O	P60	P58	H10	P85	286 (3)
I/O	-	P59	H11	P86	289 (3)
I/O	-	P60	H12	P87	292 (3)
I/O (D4(2))	P61	P61	H13	P88	295 (3)
I/O	P62	P62	G12	P89	298 (3)
VCC	P63	P63	G13	P90	-
GND	P64	P64	G11	P91	-
I/O (D3(2))	P65	P65	G10	P92	301 (3)
I/O	P66	P66	F13	P93	304 (3)
I/O	-	P67	F12	P94	307 (3)
I/O	-	-	F11	P95	310 (3)
I/O (D2(2))	P67	P68	F10	P96	313 (3)
I/O	P68	P69	E13	P97	316 (3)
I/O	-	-	E12	P98	319 (3)
I/O	-	-	E11	P99	322 (3)
GND	-	-	E10	P100	-
I/O (D1(2))	P69	P70	D13	P101	325 (3)
I/O	P70	P71	D12	P102	328 (3)
I/O	-	-	D11	P103	331 (3)
I/O	-	-	C13	P104	334 (3)
I/O (D0(2), DIN)	P71	P72	C12	P105	337 (3)
I/O, SGCK4(1) GCK6(2) (DOUT)	P72	P73	C11	P106	340 (3)
CCLK	P73	P74	B13	P107	-
VCC	P74	P75	B12	P108	-
O, TDO	P75	P76	A13	P109	0
GND	P76	P77	A12	P110	-
I/O	P77	P78	B11	P111	2
I/O, PGCK4(1) GCK7(2)	P78	P79	A11	P112	5
I/O	-	-	D10	P113	8
I/O	-	-	C10	P114	11
I/O (CS1(2))	P79	P80	B10	P115	14

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100(5)	TQ144	PQ208	PQ240	BG256(5)	CS280(2,5)	Bndry Scan
I/O	-	-	P124	P144	M20	L19	493 (3)
I/O	-	-	P125	P145	L19	L18	496 (3)
I/O	P59	P86	P126	P146	L18	L17	499 (3)
I/O	P60	P87	P127	P147	L20	L16	502 (3)
I/O (D4(2))	P61	P88	P128	P148	K20	K19	505 (3)
I/O	P62	P89	P129	P149	K19	K18	508 (3)
VCC	P63	P90	P130	P150	VCC(4)	K17	-
GND	P64	P91	P131	P151	GND(4)	GND(4)	-
I/O (D3(2))	P65	P92	P132	P152	K18	K16	511 (3)
I/O	P66	P93	P133	P153	K17	K15	514 (3)
I/O	P67	P94	P134	P154	J20	J19	517 (3)
I/O	-	P95	P135	P155	J19	J18	520 (3)
I/O	-	-	P136	P156	J18	J17	523 (3)
I/O	-	-	P137	P157	J17	J16	526 (3)
I/O (D2(2))	P68	P96	P138	P159	H19	H17	529 (3)
I/O	P69	P97	P139	P160	H18	H16	532 (3)
VCC	-	-	P140	P161	VCC(4)	G19	-
I/O	-	P98	P141	P162	G19	G18	535 (3)
I/O	-	P99	P142	P163	F20	G17	538 (3)
I/O	-	-	-	P164	G18	G16	541 (3)
I/O	-	-	-	P165	F19	F19	544 (3)
GND	-	P100	P143	P166	GND(4)	GND(4)	-
I/O	-	-	-	P167	F18	F18	547 (3)
I/O	-	-	P144	P168	E19	F17	550 (3)
I/O	-	-	P145	P169	D20	F16	553 (3)
I/O	-	-	P146	P170	E18	F15	556 (3)
I/O	-	-	P147	P171	D19	E19	559 (3)
I/O	-	-	P148	P172	C20	E17	562 (3)
I/O (D1(2))	P70	P101	P149	P173	E17	E16	565 (3)
I/O	P71	P102	P150	P174	D18	D19	568 (3)
I/O	-	P103	P151	P175	C19	C19	571 (3)
I/O	-	P104	P152	P176	B20	B19	574 (3)
I/O (D0(2), DIN)	P72	P105	P153	P177	C18	C18	577 (3)
I/O, SGCK4(1), GCK6(2) (DOUT)	P73	P106	P154	P178	B19	B18	580 (3)
CCLK	P74	P107	P155	P179	A20	A19	-
VCC	P75	P108	P156	P180	VCC(4)	C17	-
O, TDO	P76	P109	P157	P181	A19	B17	0
GND	P77	P110	P158	P182	GND(4)	GND(4)	-
I/O	P78	P111	P159	P183	B18	A18	2
I/O, PGCK4(1), GCK7(2)	P79	P112	P160	P184	B17	A17	5
I/O	-	P113	P161	P185	C17	D16	8
I/O	-	P114	P162	P186	D16	C16	11
I/O (CS1)(2)	P80	P115	P163	P187	A18	B16	14
I/O	P81	P116	P164	P188	A17	A16	17
I/O	-	-	P165	P189	C16	D15	20